

• General Description

The AGM1065M combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{\text{DS(ON)}}$.

This device is ideal for load switch and battery protection applications.

Features

- Advance high cell density Trench technology
- Low R_{DS(ON)} to minimize conductive loss
- ■Low Gate Charge for fast switching
- ■Low Thermal resistance
- ■100% Avalanche tested
- ■100% DVDS tested

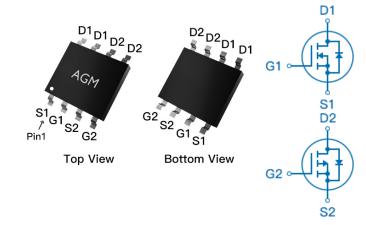
Application

- ■MB/VGA Vcore
- ■SMPS 2nd Synchronous Rectifier
- ■POL application
- ■BLDC Motor driver

Product Summary

BVDSS	RDSON	ID
100V	87mΩ	10A
-100V	115mΩ	-9A

SOP8 Pin Configuration



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
AGM1065M	AGM1065M	SOP8	330mm	12mm	3000

Table 1. Absolute Maximum Ratings (TA=25°C)

		Rating		
Symbol	Parameter	N-Ch	P-Ch	Units
V _{DS}	Drain-Source Voltage (V _{GS} =0V)	100	-100	V
VGS	Gate-Source Voltage (V _{DS=} 0V)	±20	±20	V
ID	Drain Current-Continuous(TA=25℃) (Note 1)	10	-9.0	А
	Drain Current-Continuous(TA=100°C)	6.7	-6.0	Α
IDM (pluse)	Drain Current-Pulsed (Note 2)	40	-36	Α
PD	Total Power Dissipation(TA=25℃)	2.5	2.5	W
EAS	Avalanche energy (Note 3)	26	26	mJ
TJ,TSTG	Operating Junction and Storage Temperature Range	-55 To 150	-55 To 150	$^{\circ}$ C

Table 2. Thermal Characteristic

Symbol	Parameter	Тур	Max	Unit
R _{0JA}	Thermal Resistance Junction-ambient (Steady State) ¹		50	°C/W



Table 3. N- Channel Electrical Characteristics (TJ=25°cunless otherwisenoted)

Symbol	- Channel Electrical Characteris Parameter	Conditions	Min	Тур	Max	Unit
On/Off State	es					
BVDSS	Drain-Source Breakdown Voltage	VGS=0V ID=250µA	100			V
IDSS	Zero Gate Voltage Drain Current	VDS=100V,VGS=0V			1	μA
IGSS	Gate-Body Leakage Current	VGS=±20V,VDS=0V			±100	nA
VGS(th)	Gate Threshold Voltage	VDS=VGS,ID=250µA	1.2		2.2	V
gFS	Forward Transconductance	VDS=5V,ID=3A				S
RDS(on)	Drain-Source On-State Resistance	VGS=10V, ID=6A		87	108	mΩ
1.50(011)		VGS=4.5V, ID=3A		90	110	mΩ
Dynamic C	Characteristics					
Ciss	Input Capacitance			845		pF
Coss	Output Capacitance	VDS=40V,VGS=0V, F=1MHZ		41		pF
Crss	Reverse Transfer Capacitance			12		pF
Rg	Gate resistance	VGS=0V, VDS=0V,f=1.0MHz				Ω
Switching	Times					
td(on)	Turn-on Delay Time			6.0		nS
tr	Turn-on Rise Time	VGS=10V,VDS=50V,		7.0		nS
td(off)	Turn-Off Delay Time	ID=3A,RGEN=1.8Ω		21		nS
tf	Turn-Off Fall Time			3.0		nS
Qg	Total Gate Charge			20		nC
Qgs	Gate-Source Charge	VGS=10V, VDS=50V, ID=2A		2.8		nC
Qgd	Gate-Drain Charge	- ID-2/\		4.0		nC
Source-Drain Diode Characteristics						
ISD	Source-Drain Current(Body Diode)				10	Α
VSD	Forward on Voltage	VGS=0V,IS=6A			1.2	V
trr	Reverse Recovery Time	IF=6A , dl/dt=100A/μs ,		22		ns
Qrr	Reverse Recovery Charge	TJ=25℃		29		nc

Notes 1. The maximum current rating is package limited.

Notes 2. Repetitive Rating: Pulse width limited by maximum junction temperature.

Notes 3.EAS condition: TJ=25 $^{\circ}\text{C}$, VDD=50V,Vgs=10V,ID=23A, L=0.1mH,RG=25ohm



Symbol	Parameter	Conditions	Min	Тур	Max	Unit
On/Off States						
BVDSS	Drain-Source Breakdown Voltage	VGS=0V ID=-250μA	-100			V
IDSS	Zero Gate Voltage Drain Current	VDS=-100V,VGS=0V			-1	μA
IGSS	Gate-Body Leakage Current	VGS=±20V,VDS=0V			±100	nA
VGS(th)	Gate Threshold Voltage	VDS=VGS,ID=-250μA	-1.2		-2.2	V
gFS	Forward Transconductance	VDS=-5V,ID=-3A				S
RDS(on)	Drain-Source On-State Resistance	VGS=-10V, ID=-6A		115	150	mΩ
1100(011)	Brain Course on Clare Nociolarico	VGS=-4.5V, ID=-3A		130	165	mΩ
Dynamic (Characteristics					
Ciss	Input Capacitance			675		pF
Coss	Output Capacitance	VDS=-40V, VGS=0V, F=1MHZ		54		pF
Crss	Reverse Transfer Capacitance	_		6.5		pF
Rg	Gate resistance	VGS=0V, VDS=0V,f=1.0MHz		18		Ω
Switching	Times					
td(on)	Turn-on Delay Time			5.9		nS
tr	Turn-on Rise Time	VGS=-10V,VDS=-50V,		3.7		nS
td(off)	Turn-Off Delay Time	ID=-5A,RGEN=5Ω		39.5		nS
tf	Turn-Off Fall Time			24.5		nS
Qg	Total Gate Charge			11.1		nC
Qgs	Gate-Source Charge	VGS=-10V, VDS=-50V, ID=-5A		2.3		nC
Qgd	Gate-Drain Charge			1.9		nC
Source-Drain Diode Characteristics						
ISD	Source-Drain Current(Body Diode)				-9.0	А
VSD	Forward on Voltage	VGS=0V,IS=-6A			-1.2	V
trr	Reverse Recovery Time	IF=-6A , dl/dt=100A/μs ,		66		ns
Qrr	Reverse Recovery Charge	TJ=25℃		214		nc

Notes 1. The maximum current rating is package limited.

 $Notes\ 2. Repetitive\ Rating: Pulse\ width\ limited\ by\ maximum\ junction\ temperature.$

Notes 3.EAS condition: TJ=25 $^{\circ}\text{C}$,VDD=-50V,Vgs=-10V,ID=-23A, L=0.1mH,RG=25ohm



Typical Performance Characteristics

Figure 1: Output Characteristics

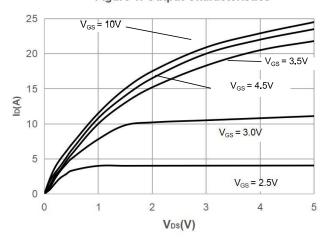


Figure 2: Typical Transfer Characteristics

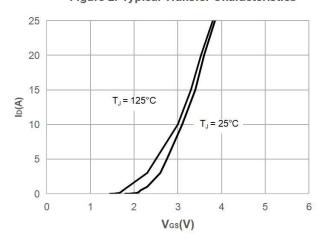


Figure 3: On-resistance vs. Drain Current

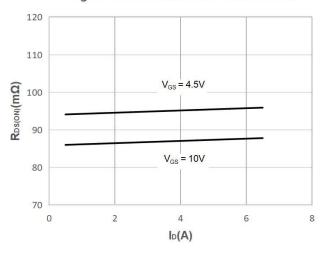


Figure 4: Body Diode Characteristics

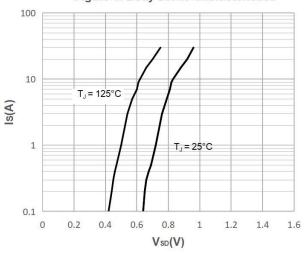


Figure 5: Gate Charge Characteristics

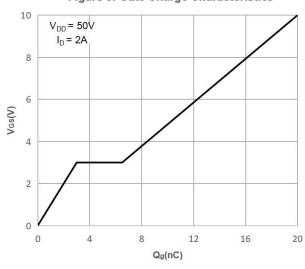
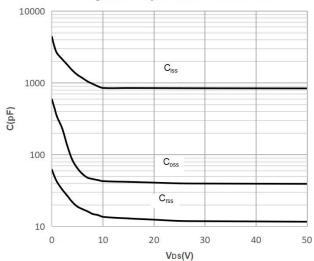


Figure 6: Capacitance Characteristics





Typical Performance Characteristics

Figure 7: Normalized Breakdown voltage vs.
Junction Temperature

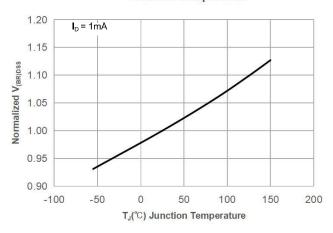


Figure 9: Maximum Safe Operating Area

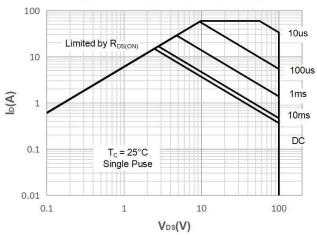


Figure 11: Normalized Maximum Transient Thermal Impedance

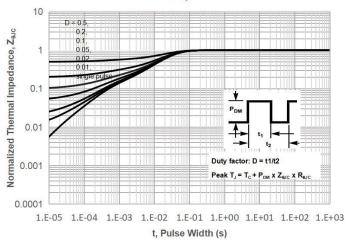


Figure 8: Normalized on Resistance vs.

Junction Temperature

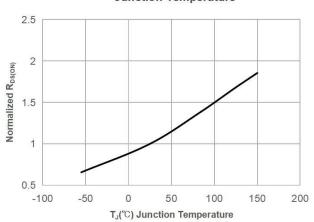


Figure 10: Maximum Continuous Drian Current vs. Case Temperature

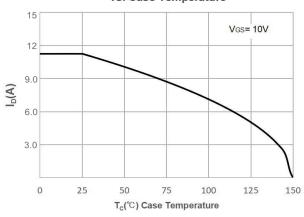
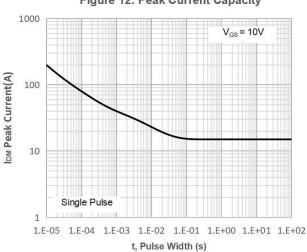


Figure 12: Peak Current Capacity





Test Circuit

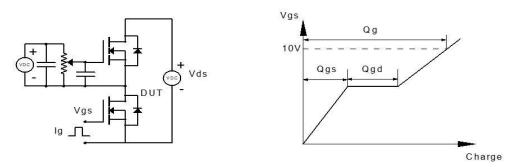


Figure 1: Gate Charge Test Circuit & Waveform

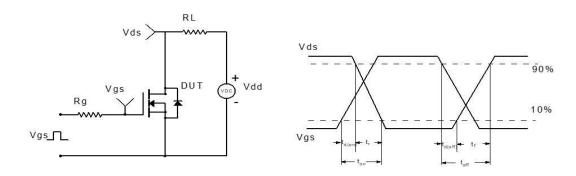


Figure 2: Resistive Switching Test Circuit & Waveform

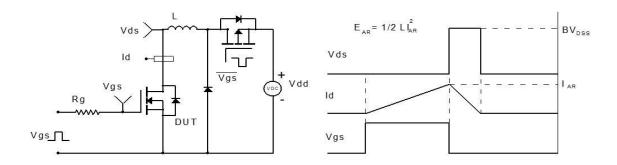


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

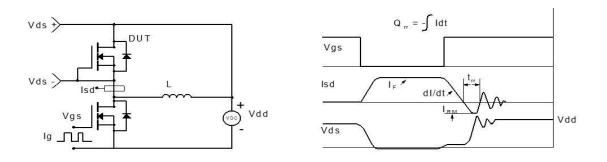
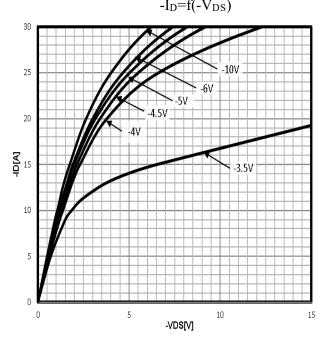


Figure 4: Diode Recovery Test Circuit & Waveform

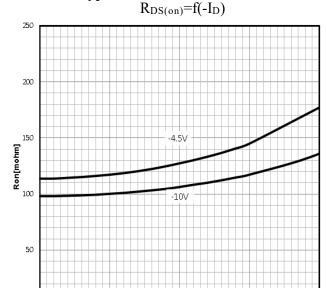


Characteristics Curve:

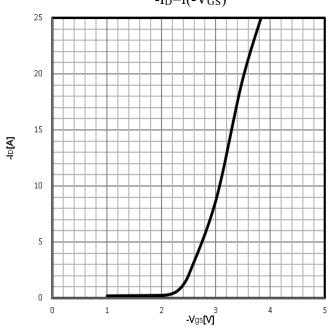
Typ. output characteristics $-I_D = f(-V_{DS})$



Typ. drain-source on resistance



Typ. transfer characteristics $-I_D = f(-V_{GS})$

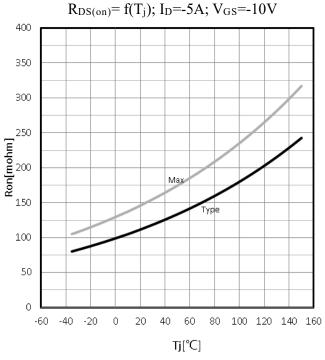


Drain-source on-state resistance

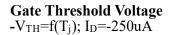
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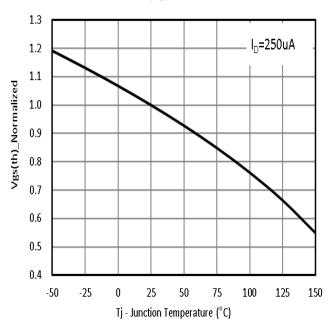
10

ID[A]



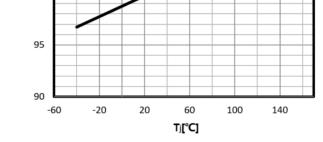




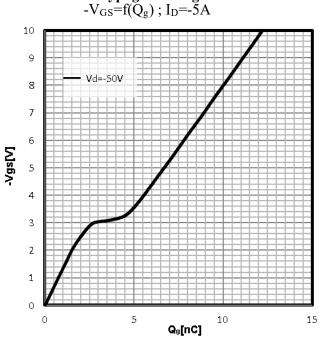


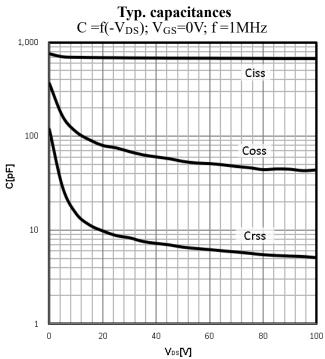
$\begin{array}{c} \textbf{Drain-source breakdown voltage} \\ \textbf{-}V_{BR(DSS)} \!\!=\!\! f(T_j); \ I_D \!\!=\!\! -250 uA \end{array}$



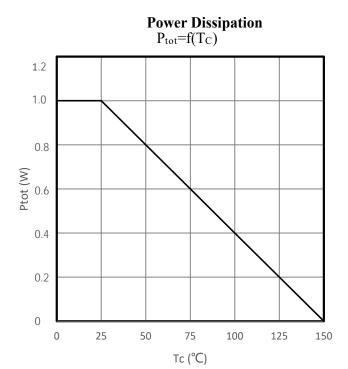


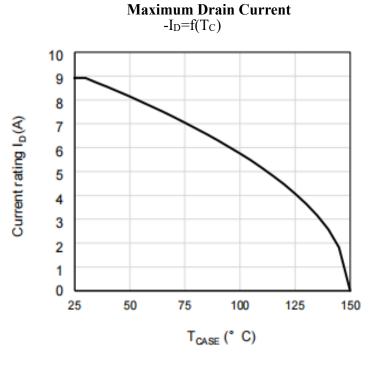
Typ. gate charge $-V_{GS}=f(Q_g)$; $I_D=-5A$

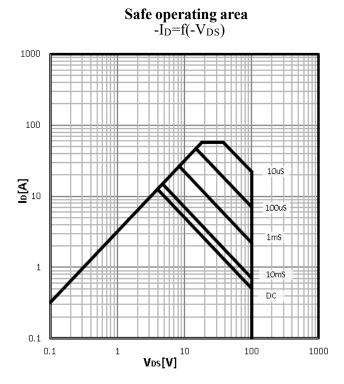


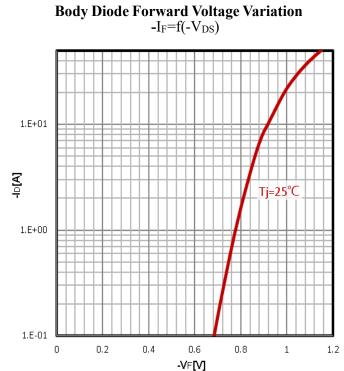




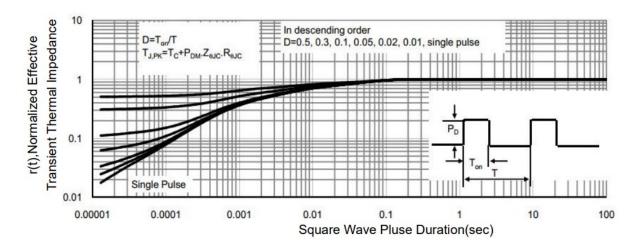






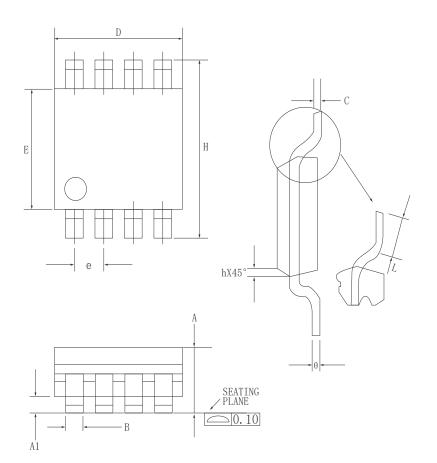




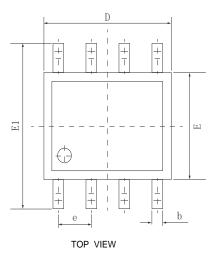


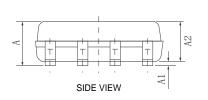


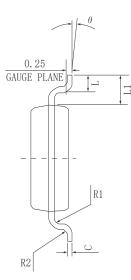
•Dimensions (SOP8)



	MILLIM	ETEDDC	
DIM	MILLIMETERRS		
	MIN	MAX	
A	1.35	1. 75	
A1	0.02	0.15	
В	0.33	0.5	
С	0.1	0.25	
D	4.8	5	
Е	3.8	4	
е	1.27(BSC)	
Н	5. 8	6. 2	
h	0. 25	0.5	
Ι	0.4	1. 25	
θ	0°	7°	



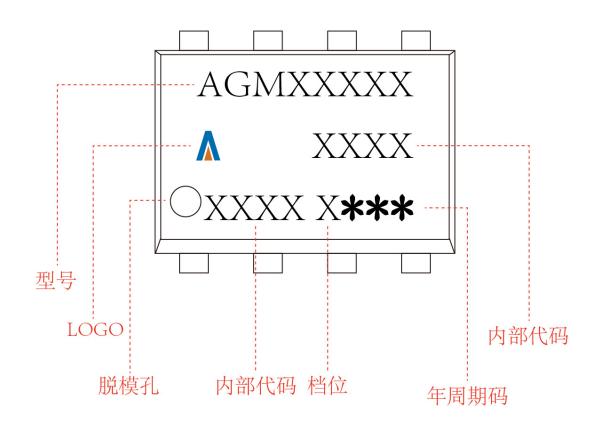




SYMBOL	MIN	NOM	MAX	
A	1.40	1.60	1.80	
A1	0.05	0.15	0.25	
A2	1.35	1.45	1.55	
b	0.30	0.40	0.50	
С	0.153	0. 203	0. 253	
D	4.80	4.90	5.00	
Е	3.80	3.90	4.00	
E1	5. 80	6.00	6. 20	
L	0.45	0.70	1.00	
θ	2°	4°	6°	
L1	1.04 REF			
е	1.27 BSC			
R1	0.07 TYP			
R2	0.07 TYP			



SOP8
Marking Instructions:





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